

New Developments in ED-XRF Technology Enable Highly Precise Elemental Analyses

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Laboratories utilizing X-ray Fluorescence often opt for traditional high power wavelength dispersive x-ray fluorescence (WD-XRF) instrumentation due to the high precision that these instruments offer.

New developments in ED-XRF technology allow for extremely precise measurements that are comparable to WD-XRF. This technology provides outstanding stability in highly demanding applications requiring the sensitivity and precision necessary for analysis of major and minor elements in samples such as cement, slag, refractory products, geological applications, and many more.

